

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/019,052 NEW ET AL.	
		Examiner	Art Unit	Page 1 of 1 Mark L. Shibuya

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0095962	05-2003	Ueda et al.	424/130.1
*	B	US-5,851,536	12-1998	Yager et al.	424/400
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 95/02684 A1	01-1995	WIPO	CRABTREE et al.	C12N 5/00
	O	WO 96/23881 A1	08-1996	WIPO	CAPON et al.	C12N 15/12
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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